

## Referencias

1. Belsley, D., Kuh, y Welsh, R. (1980) Regression Diagnostics. John Wiley, New York.
2. Draper, N y Smith, H. (1998). Applied Regression Analysis, Third Edition. John Wiley, New York.
3. Haerdle, W. (1990). Applied nonparametric Regression. Cambridge University Press. New York.
4. Hastie, T. y Tibshirani, R. (1990). Generalized additive models. Chapman and Hall, London.
5. Hosner, D y Lemeshow, S. (2000). Applied Logistic Regression. Second Edition. John Wiley, New York.
6. Myers, R. (1990). Classical and Modern Regression with applications. Duxbury Press, Belmont, California.
7. Neter, J., Wasserman, W., Kutner, M.H, y Nachtsheim, C. (1996). Applied Linear Statistical Models, McGraw-Hill, Boston
8. Rao, C.R. (1973). Linear Statistical Inference and its applications. John Wiley and Sons, New York.
9. Rawlings, J.O., Sastry, G.P. y Dickey D.A (1998), Applied Regression Analysis: A Research Tool, Springer-Verlag, New York.
10. Rousseeuw, P. y Leroy A. (1987). Robust Regression and outlier detection . John Wiley. New York.
- 11 Ryan, T. (1996). .Modern Regression Methods. John Wiley, New York.
12. Seber, G.A.F (1977) Linear Regression Analysis. John Wiley, New York.
13. Weisberg, S. (1985). Applied Linear Regression. Second Edition. John Wiley, New York.
14. Venables, W.N. and Ripley B.D. (1997) Modern Applied Statistics with S-Plus. Second Edition. Springer-Verlag, New York.